



SHEET 1 OF 1

INFORMATION DISCLOSURE
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APPLICANT
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TJ		JP 11-54798	02/26/1999	TOSHIBA CORP.		JAPAN (w/English Abstract)
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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
TJ		HASHIZUME, T., et al. "Characterization of GaN and AlGaN Surfaces and Their Insulated Gate Structures." The Institute of Electronics, Information and Communication Engineers. Technical Report of IEICE., ED2002-87, LQE2002-82 (2002-08). Pp. 57-60, June 14, 2002.
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EXAMINER

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06-09-2005

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